

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10654954	CHEN ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Meless N Zewdu	2617

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
455	127.5, 343.1-343.5, 515-517, 528, 550.1, 556.2, 560-561, 571-574	3/30/08	M.Z.
370	311-314, 328-329, 338	3/30/08	M.Z.
713	300, 310, 321-324	3/30/08	M.Z.
340	7.32-7.39, 539.3, 693.3-693.4	3/30/08	M.Z.
342	385-386	3/30/08	M.Z.

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Searched: US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT & IBM_TDB	3/30/08	m.z.
Searched: broad textual search; class-subclass search; inventor search and assignee search	3/30/08	M.Z.

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
455	127.5, 343.2, 574	3/30/08	M.Z.
370	311, 338	3/30/08	M.Z.